Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO.		SERIAL NO. 10/662, 309					
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EXAMINER		DOCUMENT	DATE	NAME	CLASS	SUB	FILING DATE				
INITIAL		NUMBER	DATE	NAME	CLASS	CLASS	IF APPROPRIATE				
TL	AA	2002/0120895 A1	08/02	Suzuki							
TL	AB	2001/0047499 A1	11/01	Whetsel, JR	ļ						
TL	AC	6,445,627	09/02	Nakahara et ai							
TL	AD	6,408,414	06/02	Hatada							
TU	AE	6,154,396	11/00	Yabe et al							
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		OTHER RE	FERENCES (	Including Author, Title, Date, Pertinen	Pages, e	tc.)					
TL	AW	Jun OHTANI, et al. " A Shared Built-In Self-Repair Analysis for Multiple Embedded Memories," IEEE 2001 CUSTOM INTEGRATED CIRCUITS CONFERENCE. 2001, pp.187-190									
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